Design of Digital Systems II Sequential Logic Design Principles (1)

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Resource: "Digital Design: Principles & Practices"

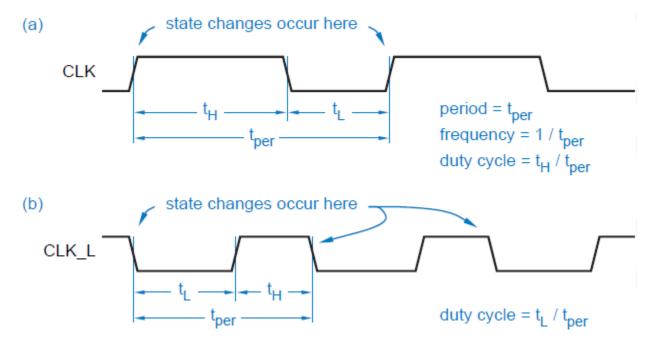
by John F. Wakerly

Introduction

- Logic circuits are classified into two types, "combinational" and "sequential".
- A combinational logic circuit is one whose outputs depend only on its current inputs.
- A **sequential** logic circuit is one whose outputs depend not only on its current inputs, but also on past sequence of inputs, possibly arbitrarily far back in time.
- So it is **inconvenient**, and often impossible, to describe behavior of a sequential circuit by means of a **table** that lists outputs as a function of input sequence that has been received up until current time.
- State of a sequential circuit is a collection of state variables whose values at any
 one time contain all information about past necessary to account for circuit's
 future behavior.
- In a digital logic circuit, **state variables are binary values**, corresponding to certain logic signals in circuit.
- A circuit with n binary state variables has 2^n possible states.

Introduction

- State changes of most sequential circuits occur at times specified by a free-running clock signal.
- Clock signals: (a) active high (b) active low:



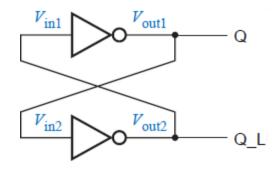
- By convention, a clock signal is active high if state changes occur at clock's rising edge or when clock is HIGH, and active low in complementary case.
- First edge or pulse in a clock period or sometimes period itself is called a **clock tick**.

Introduction

- There are generally two types of sequential circuits:
 - 1) **feedback sequential circuit** which uses ordinary gates and feedback loops to obtain memory in a logic circuit, thereby creating sequential circuit building blocks such as latches and flip-flops that are used in higher-level designs.
 - 2) **clocked synchronous state machine** which uses these building blocks, in particular edge-triggered D flip-flops, to create circuits whose inputs are examined and whose outputs change in accordance with a controlling clock signal.

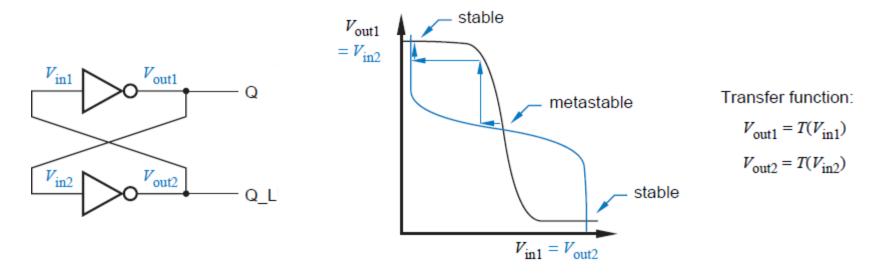
Bistable Elements: Digital Analysis

Simplest sequential circuit (it has no inputs):



- This circuit is often called a bistable, since a strictly digital analysis shows that it has
 two stable states.
- If Q is HIGH, bottom inverter has a HIGH input and a LOW output, which forces the top inverter's output HIGH as we assumed in first place.
- If Q is LOW, bottom inverter has a LOW input and a HIGH output, which forces Q LOW, another stable situation.
- There are two possible states, Q = 0 and Q = 1.

Bistable Elements: Analog Analysis



- Lines in figure above (right) show steady-state (DC) transfer functions T for inverters.
- Feedback loop is in equilibrium if input and output voltages of both inverters are constant DC values consistent with loop connection and inverters' DC transfer function. That is, we must have:

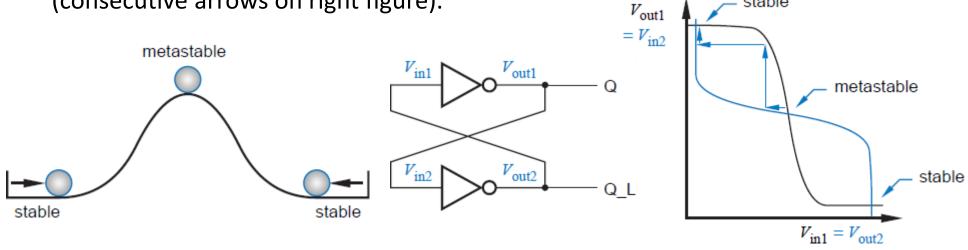
$$V_{in1} = V_{out2} = T(V_{in2}) = T(V_{out1}) = T(T(V_{in1}))$$

• Likewise we must have: $V_{in2} = T(T(V_{in2}))$

Bistable Elements: Analog Analysis

- These equilibrium points are ones in figure at which two transfer curves meet.
 There are three equilibrium points, two stable and one metastable.
- Metastable point occurs with V_{out1} and V_{out2} about halfway between a valid logic 1 voltage and a valid logic 0 voltage. Q and Q_L are not valid logic signals at this point. Yet loop equations are satisfied; if we can get circuit to operate at metastable point, it could theoretically stay there indefinitely.

Metastable point is **not truly stable**, because **random noise** will tend to drive a circuit that is operating at metastable point toward one of stable operating points (consecutive arrows on right figure).



Bistable Elements

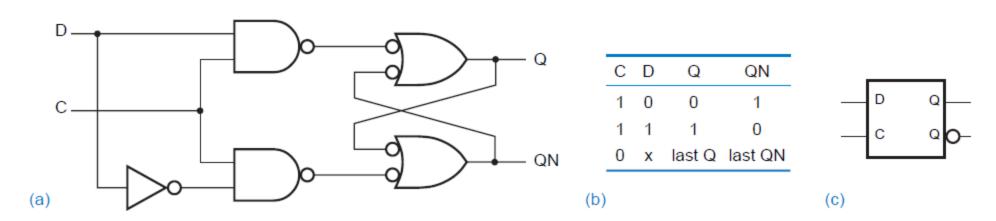
- **Bistable may stay** in **metastable** state for an **unpredictable length of time** before nondeterministically settling into one stable state or the other.
- If simplest sequential circuit is susceptible to metastable behavior, then all sequential circuits are susceptible and this behavior is not something that only occurs at power-up.
- Example: in **S-R flip-flops**, a pulse on *S* input forces flip-flop from 0 state to 1 state. A minimum pulse width is specified for *S* input.
 - 1) Apply a pulse of this width or longer, and flip-flop immediately goes to 1 state.
 - 2) Apply a very short pulse, and flip-flop stays in 0 state.
 - 3) Apply a pulse just under minimum width, and flip-flop may go into metastable state.
- Once flip-flop is in metastable state, its operation depends on "shape of its hill".

Latches and Flip-Flops

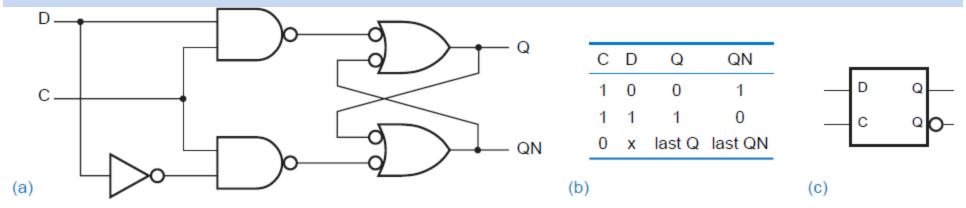
- Latches and flip-flops are basic building blocks of most sequential circuits.
- Flip-flop is a sequential device that normally samples its inputs and changes its outputs only at times determined by a clocking signal.
- Latch is a sequential device that watches all of its inputs continuously and changes its outputs at any time, independent of a clocking signal.

D Latch

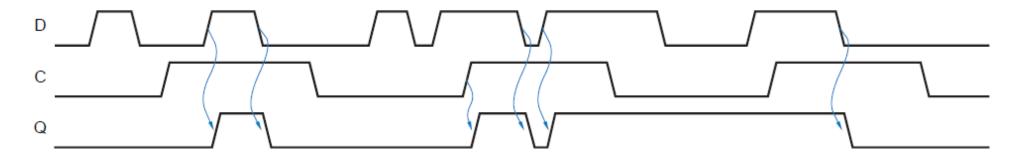
• We often need latches simply to **store bits of information**. A **D latch** may be used in such an application:



D Latch

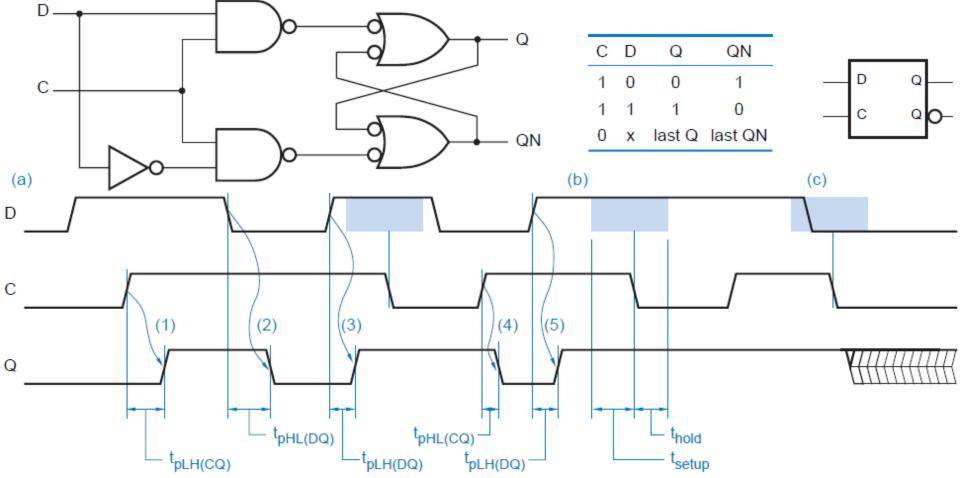


Functional behavior of a D latch for various inputs:



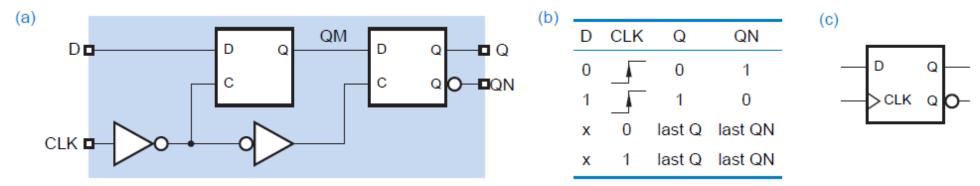
- When **C input is asserted**, Q output follows D input. In this situation, latch is said to be "open" and path from D input to Q output is "transparent"; circuit is called a "transparent latch" for this reason.
- When **C input is negated**, latch "closes"; Q output retains its last value and no longer changes in response to D, as long as C remains negated.

D Latch: Timing Parameters

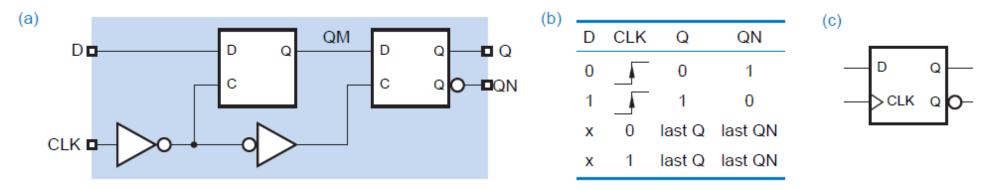


- **Setup time** (**Hold time**) is minimum amount of time the data signal should be held steady **before** (**after**) clock event so that data are reliably sampled by clock.
 - D latch does not eliminate metastability problem (unpredictable or metastable).

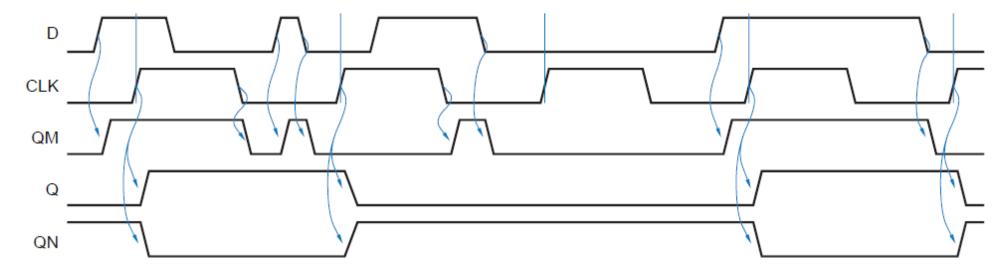
 A positive-edge-triggered D flip-flop combines a pair of D latches to create a circuit that samples its D input and changes its Q and QN outputs only at rising edge of a controlling CLK signal:

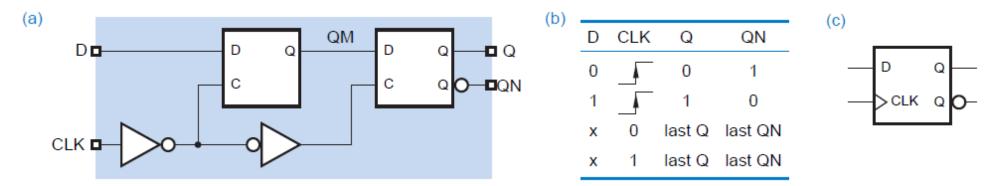


- First latch is called master; it is open and follows input when CLK is 0. When CLK goes to 1, master latch is closed and its output is transferred to second latch, called slave.
- Slave latch is open all the while that CLK is 1, but changes only at beginning of this interval, because master is closed and unchanging during rest of interval.
- Triangle on D flip-flop's CLK input indicates edge-triggered behavior, and is called a
 "dynamic-input indicator".

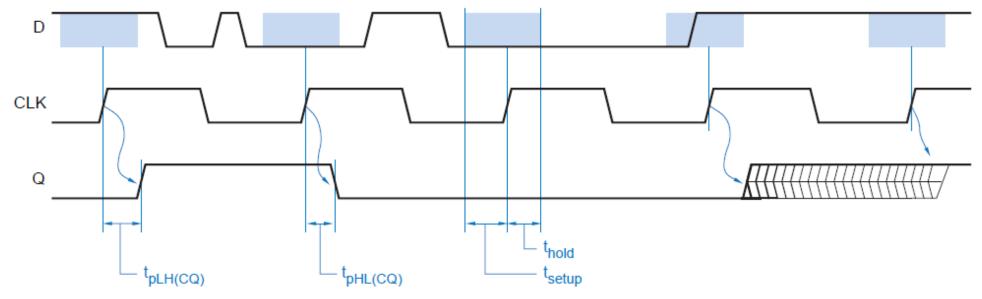


Functional behavior of a positive-edge-triggered D flip-flop:





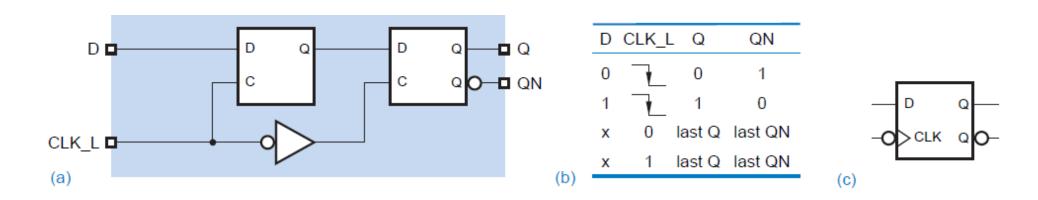
• Timing behavior of a positive-edge-triggered D flip-flop:



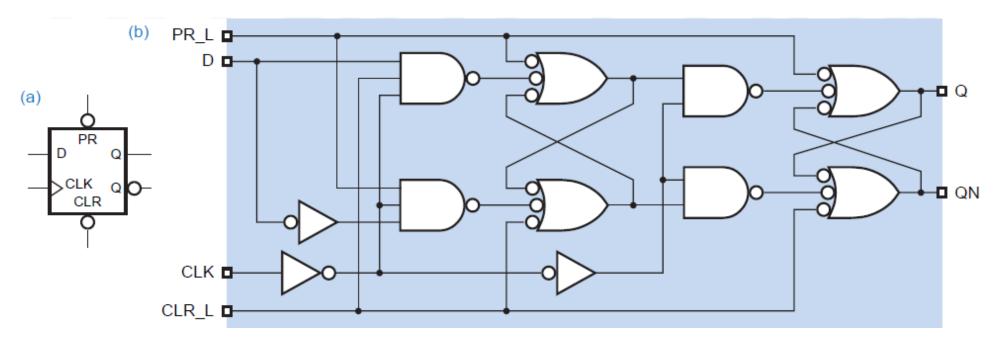
• **Different delays** may be specified for **LOW-to-HIGH** and **HIGH-to-LOW** output changes.

- Like a D latch, edge-triggered D flip-flop has a **setup and hold time window** during which D inputs must not change.
- This window occurs around triggering edge of clock.
- If **setup and hold times are not met**, flip-flop output will usually go to a **stable**, though **unpredictable**, **0 or 1 state**.
- In some cases, output will oscillate or go to a metastable state halfway between 0 and 1.
- If flip-flop goes into metastable state, it will return to a stable state on its own only after a probabilistic delay.
- It can also be **forced into a stable state** by **applying another triggering clock edge** with a D input that **meets setup- and hold-time** requirements.

• A **negative-edge-triggered D flip-flop** simply inverts clock input, so that all action takes place on falling edge of CLK_L; by convention a falling-edge trigger is considered to be active low:



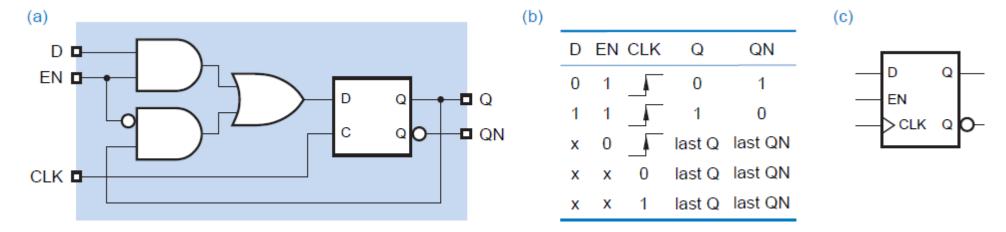
- Some D flip-flops have asynchronous inputs that may be used to force flip-flop to a
 particular state independent of CLK and D inputs.
- These inputs are typically labeled PR (preset) and CLR (clear).
- Positive-edge-triggered D flip-flop with preset and clear:



• Asynchronous inputs are usually used for **initialization** and **testing purposes**, to force a sequential circuit into a known starting state.

Edge-Triggered D Flip-Flop with Enable

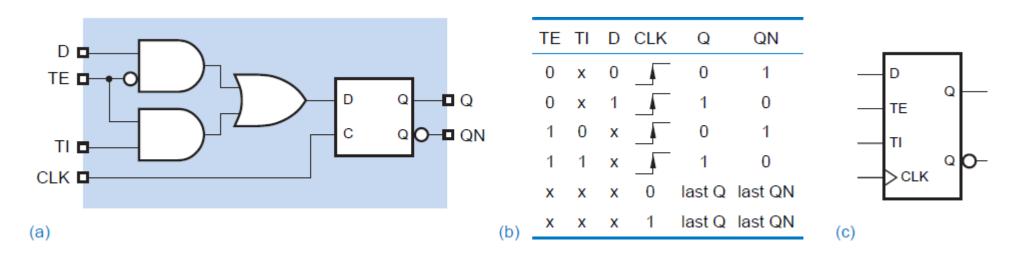
- A commonly desired function in D flip-flops is ability to hold last value stored,
 rather than load a new value, at clock edge.
- This is accomplished by adding an *enable* input.
- Positive-edge-triggered D flip-flop with enable:



A 2-input multiplexer controls value applied to internal flip-flop's D input.

- An important flip-flop function for ASIC testing is scan capability.
- Idea is to be able to **drive** flip-flop's **D input with an alternate source of data** during device testing.
- When all of flip-flops are put into testing mode, a test pattern can be "scanned in" to ASIC using flip-flops' alternate data inputs.
- After test pattern is loaded, flip-flops are put back into "normal" mode, and all of flip-flops are clocked normally.
- After one or more clock ticks, flip-flops are put back into test mode, and test results are "scanned out".

Positive-edge-triggered D flip-flop with scan:



- It is a D flip-flop with a **2-input multiplexer** on the D input.
- When TE (test enable) input is negated, circuit behaves like an ordinary D flip-flop.
 When TE is asserted, it takes its data from TI (test input) instead of from D.

• Extra inputs are used to connect all of an ASIC's flip-flops in a **scan chain** for testing purposes.

ASIC Figure 7-23 A scan chain with four flip-flops.

Property of the scan chain with four flip-flops.

Figure 7-23 A scan chain with four flip-flops.

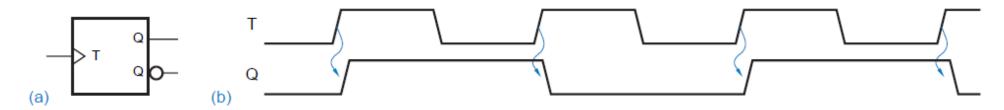
- TE inputs of all flip-flops are connected to a **global TE** input, while each flip-flop's Q output is connected to another's TI input in serial fashion.
- TI, TE, and TO (test output) connections are strictly for testing purposes.
- To test circuit, global TE input is asserted while n clock ticks occur and n test-vector bits are applied to global TI input and are thereby scanned (shifted) into n flip-flops (n = 4 in figure above).

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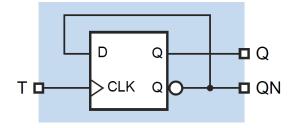
- Then TE is negated, and circuit is allowed to run for one or more additional clock ticks.
- New state of circuit, represented by new values in n flip-flops, can be observed (scanned out) at TO by asserting TE while n more clock ticks occur.
- To make testing process more efficient, another test vector can be scanned in while previous result is being scanned out.
- Scan capability can also be added to other flip-flop types.

T Flip-Flop

- A T (toggle) flip-flop **changes state on every tick** of clock.
- Positive-edge-triggered T flip-flop and its functional behavior:



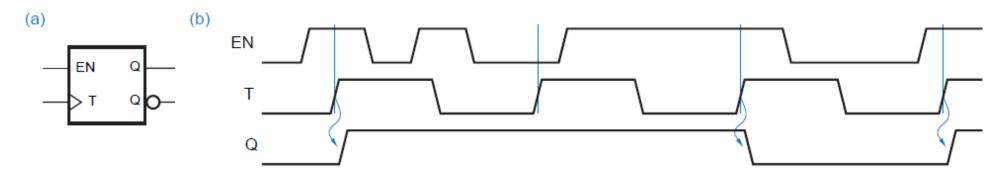
- Signal on flip-flop's Q output has precisely half frequency of T input.
- Following figure shows how to obtain a T flip-flop from a D flip-flop:



T flip-flops are most often used in counters and frequency dividers.

T Flip-Flop

- In many applications of T flip-flops, **flip-flop need not be toggled** on every clock tick. Such applications can use a **T flip-flop with enable**.
- Positive-edge-triggered T flip-flop with enable:



- Flip-flop changes state at triggering edge of clock only if enable signal EN is asserted.
- Like D input on edge-triggered D flip-flop, EN input must meet specified setup and hold times with respect to triggering clock edge.

T Flip-Flop

Possible circuit for a T flip-flop with enable:

